# BUK9620-100B N-channel TrenchMOS logic level FET

Rev. 02 — 6 May 2009

**Product data sheet** 

#### **Product profile** 1.

### 1.1 General description

Logic level N-channel enhancement mode Field-Effect Transistor (FET) in a plastic package using TrenchMOS technology. This product has been designed and qualified to the appropriate AEC standard for use in automotive critical applications.

### 1.2 Features and benefits

- AEC-Q101 compliant
- Low conduction losses due to low on-state resistance
- Suitable for logic level gate drive sources
- Suitable for thermally demanding environments due to 175 °C rating

### 1.3 Applications

- 12 V, 24 V and 42 V loads
- Automotive and general purpose power switching
- Motors, lamps and solenoids

### 1.4 Quick reference data

Table 1. **Quick reference** 

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$V_{DS}$	drain-source voltage	T <sub>j</sub> ≥ 25 °C; T <sub>j</sub> ≤ 175 °C	-	-	100	V
I <sub>D</sub>	drain current	V <sub>GS</sub> = 5 V; T <sub>mb</sub> = 25 °C; see <u>Figure 1</u> ; see <u>Figure 3</u>	-	-	63	Α
P <sub>tot</sub>	total power dissipation	T <sub>mb</sub> = 25 °C; see <u>Figure 2</u>	-	-	203	W
Static ch	aracteristics					
R <sub>DSon</sub>	drain-source on-state resistance	$V_{GS} = 4.5 \text{ V}; I_D = 25 \text{ A};$ $T_j = 25 \text{ °C}; \text{ see } \frac{\text{Figure 11}}{\text{Figure 12}};$ see Figure 12	-	16.4	22.3	mΩ
		$V_{GS} = 5 \text{ V}; I_D = 25 \text{ A};$ $T_j = 25 \text{ °C}; \text{ see } \frac{\text{Figure 12}}{\text{see } \frac{\text{Figure 11}}{\text{Figure 11}}};$	-	16.2	20	mΩ
Avalanch	ne ruggedness					
E <sub>DS(AL)S</sub>	non-repetitive drain-source avalanche energy	$\begin{split} I_D &= 63 \text{ A; } V_{sup} \leq 100 \text{ V;} \\ R_{GS} &= 50  \Omega; V_{GS} = 5 \text{ V;} \\ T_{j(init)} &= 25 ^{\circ}\text{C; } unclamped \end{split}$	-	-	222	mJ



BUK9620-100B

## 2. Pinning information

Table 2. Pinning information

Pin	Symbol	Description	Simplified outline	Graphic symbol
1	G	gate		
2	D	drain	mb	D
3	S	source		$G \longrightarrow \overline{A}$
mb	D	mounting base; connected to drain	1 3	mbb076 S
			SOT404 (D2PAK)	

## 3. Ordering information

Table 3. Ordering information

Type number	Package		
	Name	Description	Version
BUK9620-100B	D2PAK	plastic single-ended surface-mounted package (D2PAK); 3 leads (one lead cropped)	SOT404

## 4. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
$V_{DS}$	drain-source voltage	$T_j \ge 25 \text{ °C}; T_j \le 175 \text{ °C}$	-	100	V
$V_{DGR}$	drain-gate voltage	$R_{GS} = 20 \text{ k}\Omega$	-	100	V
$V_{GS}$	gate-source voltage		-15	15	V
$I_D$	drain current	T <sub>mb</sub> = 25 °C; V <sub>GS</sub> = 5 V; see <u>Figure 1</u> ; see <u>Figure 3</u>	-	63	Α
		$T_{mb}$ = 100 °C; $V_{GS}$ = 5 V; see <u>Figure 1</u>	-	45	Α
I <sub>DM</sub>	peak drain current	$T_{mb}$ = 25 °C; $t_p \le 10 \mu s$ ; pulsed; see <u>Figure 3</u>	-	253	Α
P <sub>tot</sub>	total power dissipation	T <sub>mb</sub> = 25 °C; see <u>Figure 2</u>	-	203	W
T <sub>stg</sub>	storage temperature		-55	175	°C
Tj	junction temperature		-55	175	°C
Source-dr	rain diode				
Is	source current	T <sub>mb</sub> = 25 °C	-	63	Α
I <sub>SM</sub>	peak source current	$t_p \le 10 \ \mu s$ ; pulsed; $T_{mb} = 25 \ ^{\circ}C$	-	253	Α
Avalanche	e ruggedness				
E <sub>DS(AL)S</sub>	non-repetitive drain-source avalanche energy	$I_D$ = 63 A; $V_{sup} \le$ 100 V; $R_{GS}$ = 50 $\Omega$ ; $V_{GS}$ = 5 V; $T_{j(init)}$ = 25 °C; unclamped	-	222	mJ

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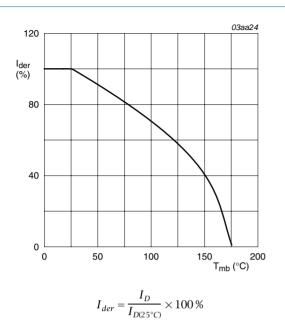


Fig 1. Normalized continuous drain current as a function of mounting base temperature

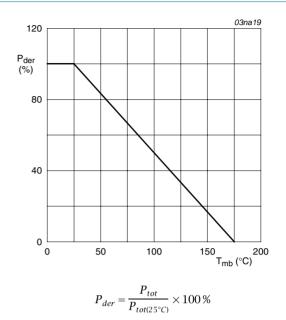
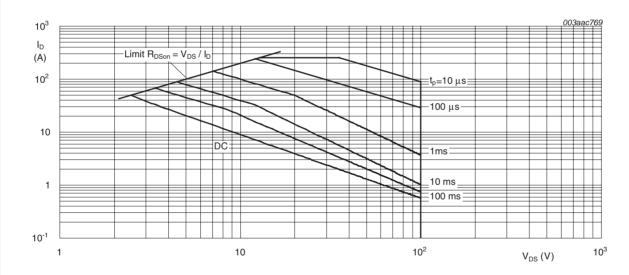


Fig 2. Normalized total power dissipation as a function of mounting base temperature



 $T_{mb} = 25$ °C;  $I_{DM}$  is single pulse

Fig 3. Safe operating area; continuous and peak drain currents as a function of drain-source voltage.

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## 5. Thermal characteristics

Table 5. Thermal characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$R_{th(j-mb)}$	thermal resistance from junction to mounting base	see Figure 4	-	-	0.75	K/W
$R_{th(j-a)}$	thermal resistance from junction to ambient	mounted on printed circuit board; minimum footprint; SOT404 package	-	50	-	K/W

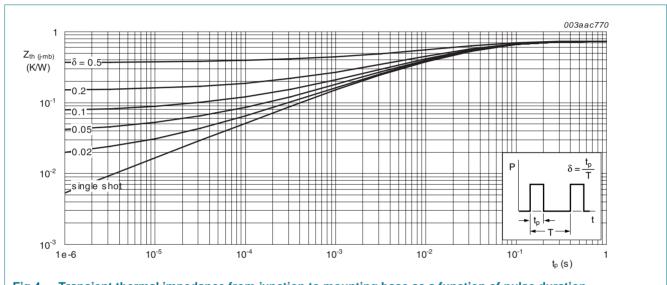


Fig 4. Transient thermal impedance from junction to mounting base as a function of pulse duration

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## 6. Characteristics

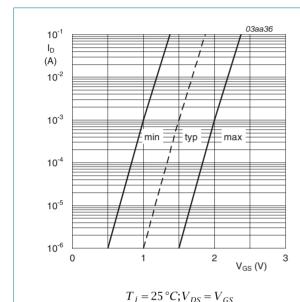
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Table 6.	Characteristics			_		
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static cha	racteristics					
$V_{(BR)DSS}$	drain-source	$I_D = 0.25 \text{ mA}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C}$	100	-	-	V
	breakdown voltage	$I_D = 0.25 \text{ mA}; V_{GS} = 0 \text{ V}; T_j = -55 \text{ °C}$	90	-	-	V
$V_{GS(th)}$	gate-source threshold voltage	$I_D = 1$ mA; $V_{DS} = V_{GS}$ ; $T_j = 25$ °C; see <u>Figure 10</u>	1	1.58	2	V
	$I_D = 1$ mA; $V_{DS} = V_{GS}$ ; $T_j = 175$ °C; see <u>Figure 10</u>	0.5	-	-	V	
		$I_D = 1$ mA; $V_{DS} = V_{GS}$ ; $T_j = -55$ °C; see <u>Figure 10</u>	-	-	2.3	V
I <sub>DSS</sub>	drain leakage current	$V_{DS} = 100 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 175 \text{ °C}$	-	-	500	μΑ
		$V_{DS} = 100 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 25 ^{\circ}\text{C}$	-	0.05	1	μΑ
I <sub>GSS</sub>	gate leakage current	$V_{DS} = 0 \text{ V}; V_{GS} = 10 \text{ V}; T_j = 25 \text{ °C}$	-	2	100	nΑ
		$V_{DS} = 0 \text{ V}; V_{GS} = -10 \text{ V}; T_j = 25 ^{\circ}\text{C}$	-	2	100	nΑ
$R_{DSon}$	drain-source on-state resistance	$V_{GS}$ = 4.5 V; $I_D$ = 25 A; $T_j$ = 25 °C; see <u>Figure 11</u> ; see <u>Figure 12</u>	-	16.4	22.3	mΩ
		$V_{GS}$ = 10 V; $I_D$ = 25 A; $T_j$ = 25 °C; see <u>Figure 11</u> ; see <u>Figure 12</u>	-	15.6	18.5	mΩ
	$V_{GS} = 5 \text{ V}; I_D = 25 \text{ A}; T_j = 175 °C;$ see <u>Figure 12</u> ; see <u>Figure 11</u>	-	-	50	mΩ	
		$V_{GS} = 5 \text{ V}; I_D = 25 \text{ A}; T_j = 25 \text{ °C};$ see Figure 12; see Figure 11	-	16.2	20	mΩ
Dynamic	characteristics					
Q <sub>G(tot)</sub>	total gate charge	$I_D = 25 \text{ A}; V_{DS} = 80 \text{ V}; V_{GS} = 5 \text{ V};$	-	53.4	-	nC
Q <sub>GS</sub>	gate-source charge	$T_j = 25 \text{ °C}$ ; see <u>Figure 14</u> ; see <u>Figure 15</u>	-	9.5	-	nC
$Q_{GD}$	gate-drain charge		-	21.2	-	nC
C <sub>iss</sub>	input capacitance	$V_{GS} = 0 \text{ V}; V_{DS} = 25 \text{ V}; f = 1 \text{ MHz};$	-	4300	5657	pF
C <sub>oss</sub>	output capacitance	T <sub>j</sub> = 25 °C; see <u>Figure 16</u>	-	340	411	pF
C <sub>rss</sub>	reverse transfer capacitance		-	150	201	pF
t <sub>d(on)</sub>	turn-on delay time	$V_{DS} = 30 \text{ V}; R_L = 1.2 \Omega; V_{GS} = 5 \text{ V};$	-	45	-	ns
t <sub>r</sub>	rise time	$R_{G(ext)} = 10 \Omega$ ; $T_j = 25 °C$	-	116	-	ns
t <sub>d(off)</sub>	turn-off delay time		-	173	-	ns
t <sub>f</sub>	fall time		-	77	-	ns
L <sub>D</sub>	internal drain inductance	from drain lead 6 mm from package to centre of die; T <sub>j</sub> = 25 °C	-	4.5	-	nΗ
		from upper edge of drain mounting base to centre of die; $T_j = 25$ °C	-	2.5	-	nΗ
L <sub>S</sub>	internal source inductance	from source lead to source bond pad; $T_j = 25 ^{\circ}\text{C}$	-	7.5	-	nΗ

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Table 6. Characteristics ... continued

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Source-dr	ain diode					
$V_{SD}$	source-drain voltage	$I_S = 25 \text{ A}; V_{GS} = 0 \text{ V}; T_j = 25 ^{\circ}\text{C};$ see <u>Figure 13</u>	-	0.86	1.2	V
t <sub>rr</sub>	reverse recovery time	$I_S = 20 \text{ A}$ ; $dI_S/dt = -100 \text{ A/}\mu\text{s}$ ; $V_{GS} = 0 \text{ V}$ ;	-	80	-	ns
Qr	recovered charge	$V_{DS} = 30 \text{ V}; T_j = 25 \text{ °C}$	-	272	-	nC



Sub-threshold drain current as a function of gate-source voltage

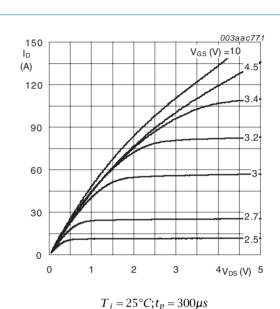


Fig 6. Output characteristics: drain current as a function of drain-source voltage; typical values

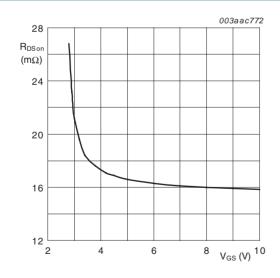


Fig 7. Drain-source on-state resistance as a function of gate-source voltage; typical values.

 $T_i = 25^{\circ}C; I_D = 25A$ 

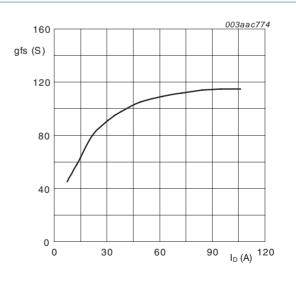


Fig 8. Forward transconductance as a function of drain current; typical values.

 $T_i = 25^{\circ}C; V_{DS} = 25V$ 

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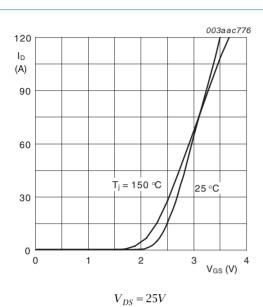


Fig 9. Transfer characteristics: drain current as a function of gate-source voltage; typical values.

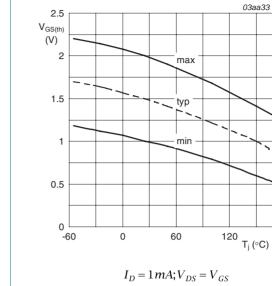


Fig 10. Gate-source threshold voltage as a function of junction temperature

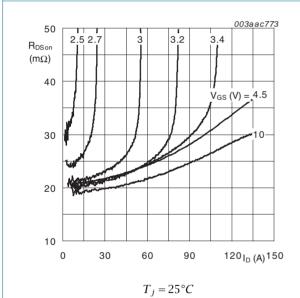
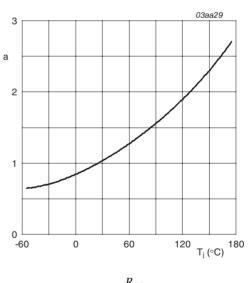


Fig 11. Drain-source on-state resistance as a function of drain current; typical values.



 $a = \frac{R_{DSon}}{R_{DSon(25^{\circ}C)}}$ 

Fig 12. Normalized drain-source on-state resistance factor as a function of junction temperature

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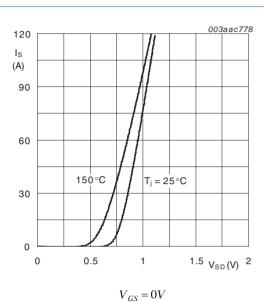


Fig 13. Source current as a function of source drain voltage; typical values.

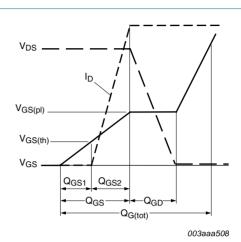


Fig 14. Gate charge waveform definitions

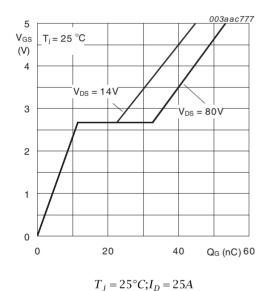


Fig 15. Gate-source voltage as a function of turn-on gate charge; typical values.

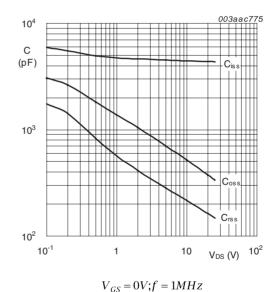


Fig 16. Input, output and reverse transfer capacitances as a function of drain-source voltage; typical values

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## 7. Package outline

## Plastic single-ended surface-mounted package (D2PAK); 3 leads (one lead cropped) **SOT404** mounting $D_1$ base $H_{D}^{\prime}$ 5 mm scale

### **DIMENSIONS** (mm are the original dimensions)

UNIT	A	A <sub>1</sub>	b	С	D max.	D <sub>1</sub>	E	е	L <sub>p</sub>	Н <sub>D</sub>	Q
mm	4.50 4.10	1.40 1.27	0.85 0.60	0.64 0.46	11	1.60 1.20	10.30 9.70	2.54	2.90 2.10	15.80 14.80	2.60 2.20

OUTLINE		REFER	EUROPEAN	ISSUE DATE		
VERSION	IEC	JEDEC	JEITA		PROJECTION	ISSUE DATE
SOT404						<del>-05-02-11-</del> 06-03-16

Fig 17. Package outline SOT404 (D2PAK)

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## 8. Revision history

### Table 7. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes
BUK9620-100B_2	20090506	Product data sheet	-	BUK9620-100B_1
Modifications:	<ul> <li>Data shee</li> </ul>	t status changed from 'Ob	jective' to 'Product'.	
BUK9620-100B_1	20090323	Objective data sheet	-	-

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### 9. Legal information

### 9.1 Data sheet status

Document status [1][2]	Product status[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

- [1] Please consult the most recently issued document before initiating or completing a design.
- [2] The term 'short data sheet' is explained in section "Definitions"
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